

## 60V,14A N-CHANNEL POWER MOSFET

### GENERAL DESCRIPTION

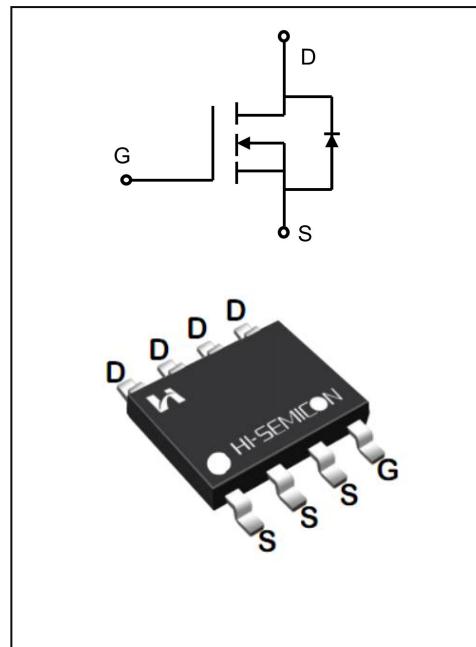
The SGS6001T4 uses advanced SGT technology and design to provide excellent  $R_{DS(on)}$  with low gate charge. It can be used in a wide variety applications.

### Features

- ◆  $V_{DS}=60V, I_D=14A$
  - ◆  $R_{DS(on)}$
- TYP:  $7.2m\Omega @ V_{GS}=10V \quad I_D=10A$

### Applications

- ◆ Power factor correction (PFC)
- ◆ Switched mode power supplies (SMPS)
- ◆ Uninterruptible power supply (UPS)
- ◆ LED lighting power



### ORDERING INFORMATION

Part No.	Package	Marking	Material	Packing
SGS6001T4	SOP8-8L	SGS6001T4	Pb Free	Reel

**ABSOLUTE MAXIMUM RATINGS (T<sub>J</sub>=25°C unless otherwise noted)**

Characteristics	Symbol	Ratings	Unit
Drain-Source Voltage	V <sub>DS</sub>	60	V
Gate-Source Voltage	V <sub>GS</sub>	±20	V
Drain Current	I <sub>D</sub>	14	A
T <sub>C</sub> = 25°C		9.2	
T <sub>C</sub> = 100°C			
Drain Current Pulsed(Note 1)	I <sub>DM</sub>	56	A
Power Dissipation(T <sub>C</sub> =25°C) -Derate above 25°C	P <sub>D</sub>	0.03	W/°C
		3.2	W
Single Pulsed Avalanche Energy (Note 2)	E <sub>AS</sub>	80	mJ
Operation Junction Temperature Range	T <sub>J</sub>	-55~+150	°C
Storage Temperature Range	T <sub>stg</sub>	-55~+150	°C
Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	TL	300	°C

 **THERMAL CHARACTERISTICS**

Characteristics	Symbol	MAX	Unit
Thermal Resistance, Junction-to-Case	R <sub>θJC</sub>	39.5	°C/W
Thermal Resistance, Junction-to-Ambient	R <sub>θJA</sub>	86	°C/W

**ELECTRICAL CHARACTERISTICS**

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
<b>Off Characteristics</b>						
Drain -Source Breakdown Voltage	B <sub>VDSS</sub>	V <sub>GS</sub> =0V I <sub>D</sub> =250μA	60	--	--	V
Drain-Source Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> =60V V <sub>GS</sub> =0V	--	--	100	nA
Gate-Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =20V V <sub>DS</sub> =0V	--	--	100	nA
Gate-Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =-20V V <sub>DS</sub> =0V	--	--	-100	nA
<b>On Characteristics</b>						
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>GS</sub> =V <sub>DS</sub> I <sub>D</sub> =250μA	1.4	1.8	2.5	V
Static Drain- Source On State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =4.5V I <sub>D</sub> =6A	--	11.5	13.5	mΩ
		V <sub>GS</sub> =10V I <sub>D</sub> =10A	--	7.2	9.5	mΩ
<b>Dynamic Characteristics</b>						
Gate Resistance	R <sub>g</sub>	V <sub>GS</sub> =0V f=1.0MHZ	1	3	10	Ω
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> =30V	--	911	--	pF
Output Capacitance	C <sub>oss</sub>		--	420	--	
Reverse Transfer Capacitance	C <sub>rss</sub>		--	38	--	
<b>Switching Characteristics</b>						
Turn-on Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> =30V V <sub>GS</sub> =10V R <sub>G</sub> =3Ω I <sub>D</sub> =13A (Note 3.4)	--	8.6	--	ns
Turn-on Rise Time	t <sub>r</sub>		--	52.3	--	
Turn-off Delay Time	t <sub>d(off)</sub>		--	21.2	--	
Turn-off Fall Time	t <sub>f</sub>		--	8.6	--	

Total Gate Charge	$Q_g$	$V_{DS}=48V$ $I_D=13A$ $V_{GS}=10V$ (Note 3.4)	--	17	--	nc
Gate-Source Charge	$Q_{gs}$		--	5.6	--	
Gate-Drain Charge	$Q_{gd}$		--	2.6	--	

## SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Continuous Source Current	$I_s$	Integral Reverse P-N Junction Diode in the MOSFET	--	--	14	A
Pulsed Source Current	$I_{SM}$		--	--	56	
Diode Forward Voltage	$V_{SD}$	$I_s=10A$ $V_{GS}=0V$	--	0.86	1.2	V
Reverse Recovery Time	$T_{rr}$	$I_F=13A$ $dI/F/dt=100A/\mu S$	--	55	--	ns
Reverse Recovery Charge	$Q_{rr}$		--	0.06	--	$\mu C$

1. Pulse width limited by maximum junction temperature

2.  $L=0.5mH$ ,  $V_{DD}=50V$ ,  $V_G=10V$ ,  $R_G=25\Omega$ , starting  $T_J=25^\circ C$ 3. Pulse Test: Pulse width  $\leq 300\mu s$ , Duty cycle  $\leq 2\%$ 

4. Essentially independent of operating temperature

## Typical Performance Characteristics

Figure 1. On-Region Characteristics

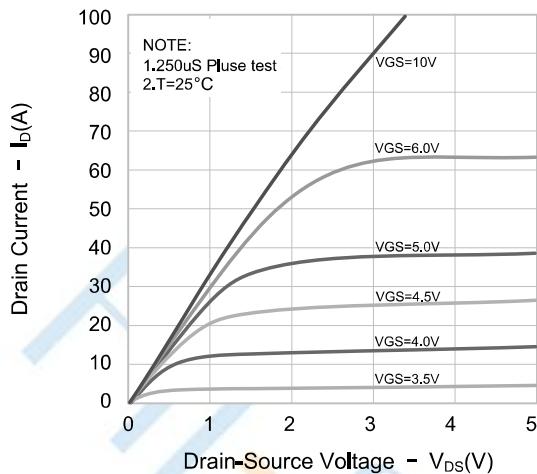


Figure 2. Transfer Characteristics

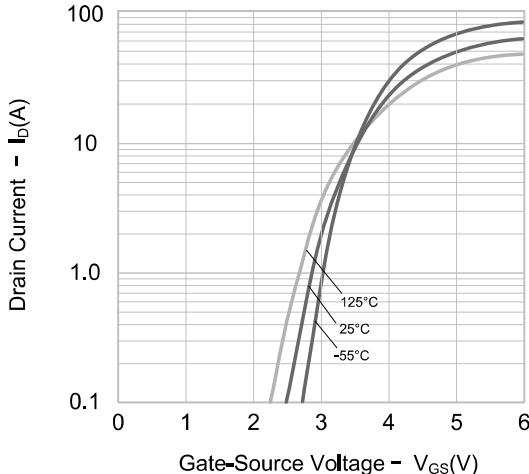


Figure 3. On-Resistance Variation vs. Drain Current

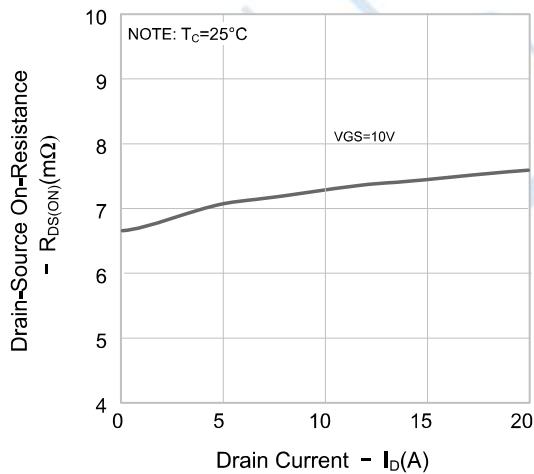


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

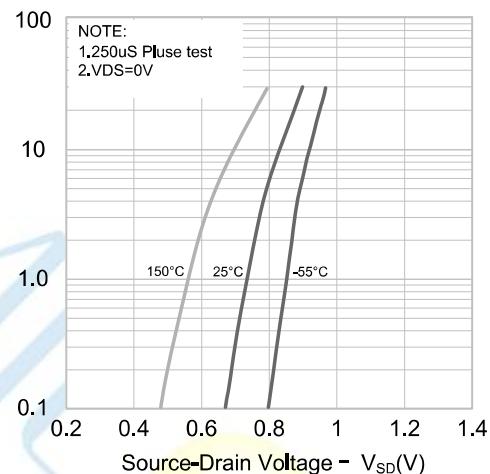


Figure 5. Capacitance Characteristics

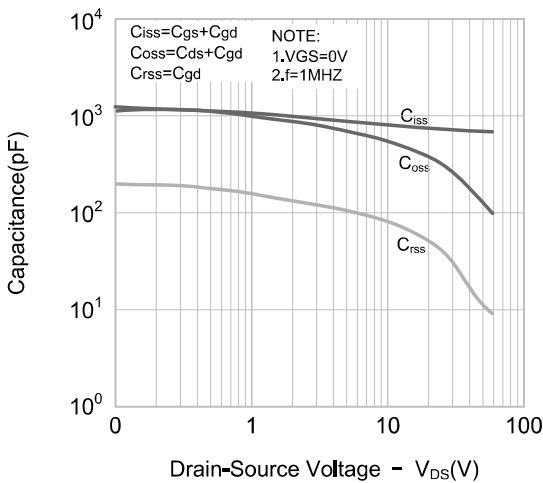
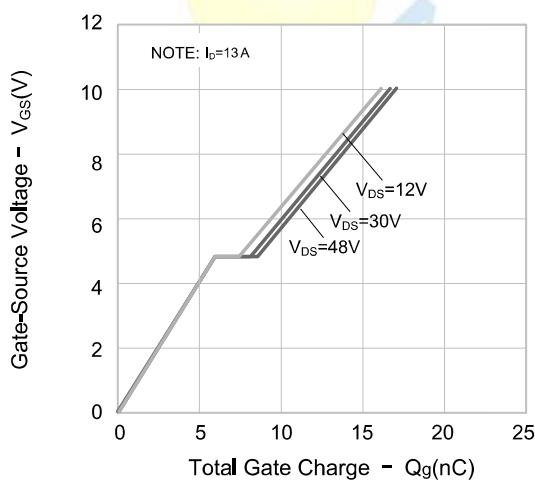


Figure 6. Gate Charge Characteristics



## Typical Performance Characteristics

Figure 7. Breakdown Voltage Variation vs. Temperature

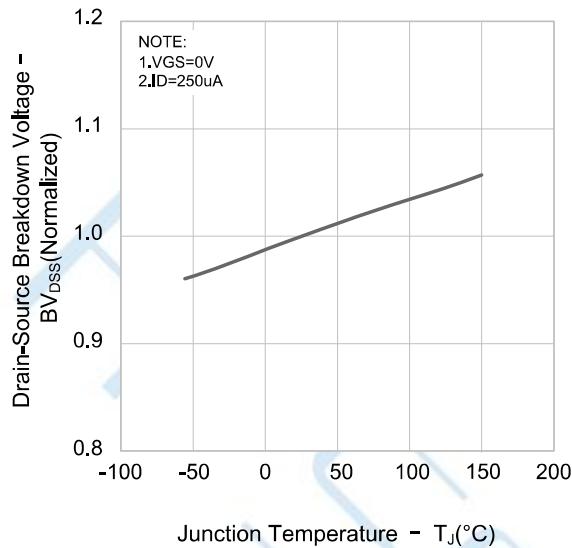


Figure 8. On-resistance Variation vs. Temperature

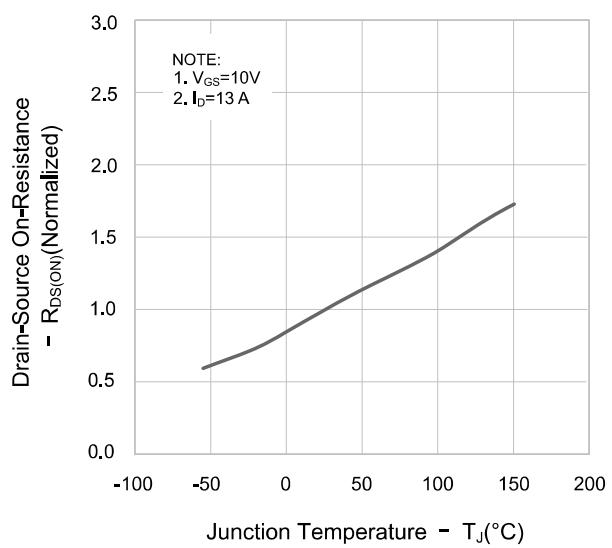
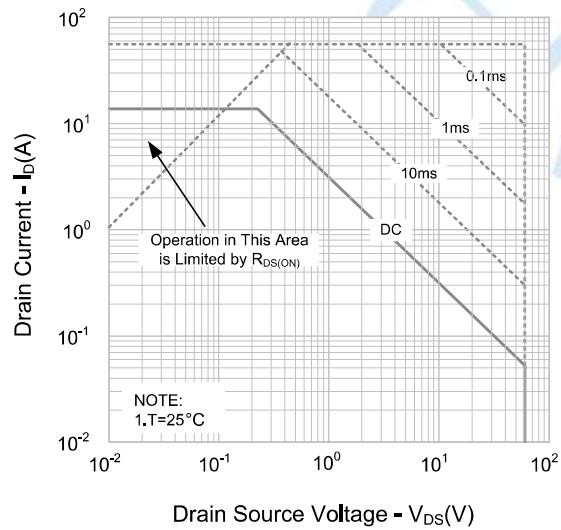
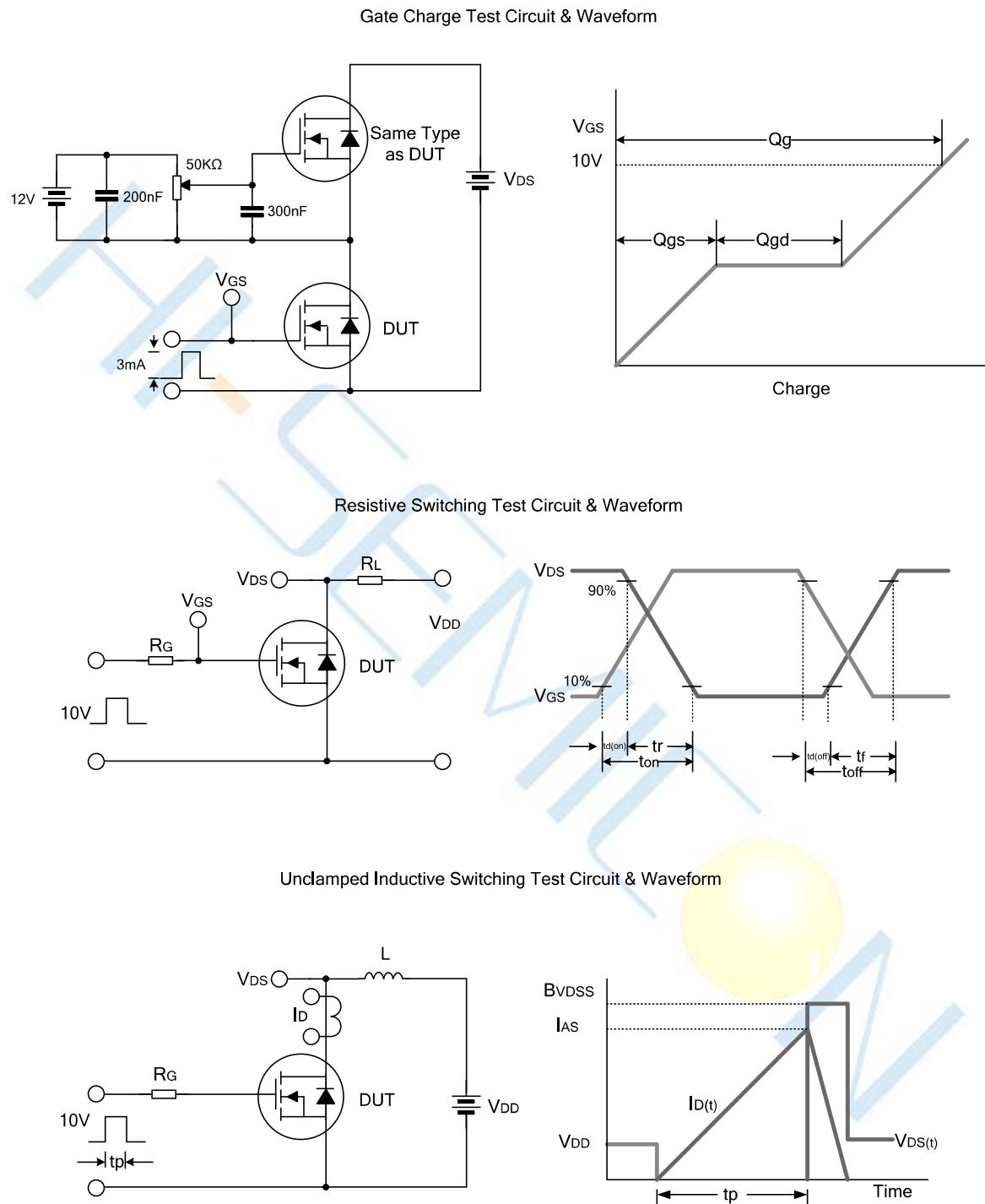


Figure 9. Max Safe Operating Area

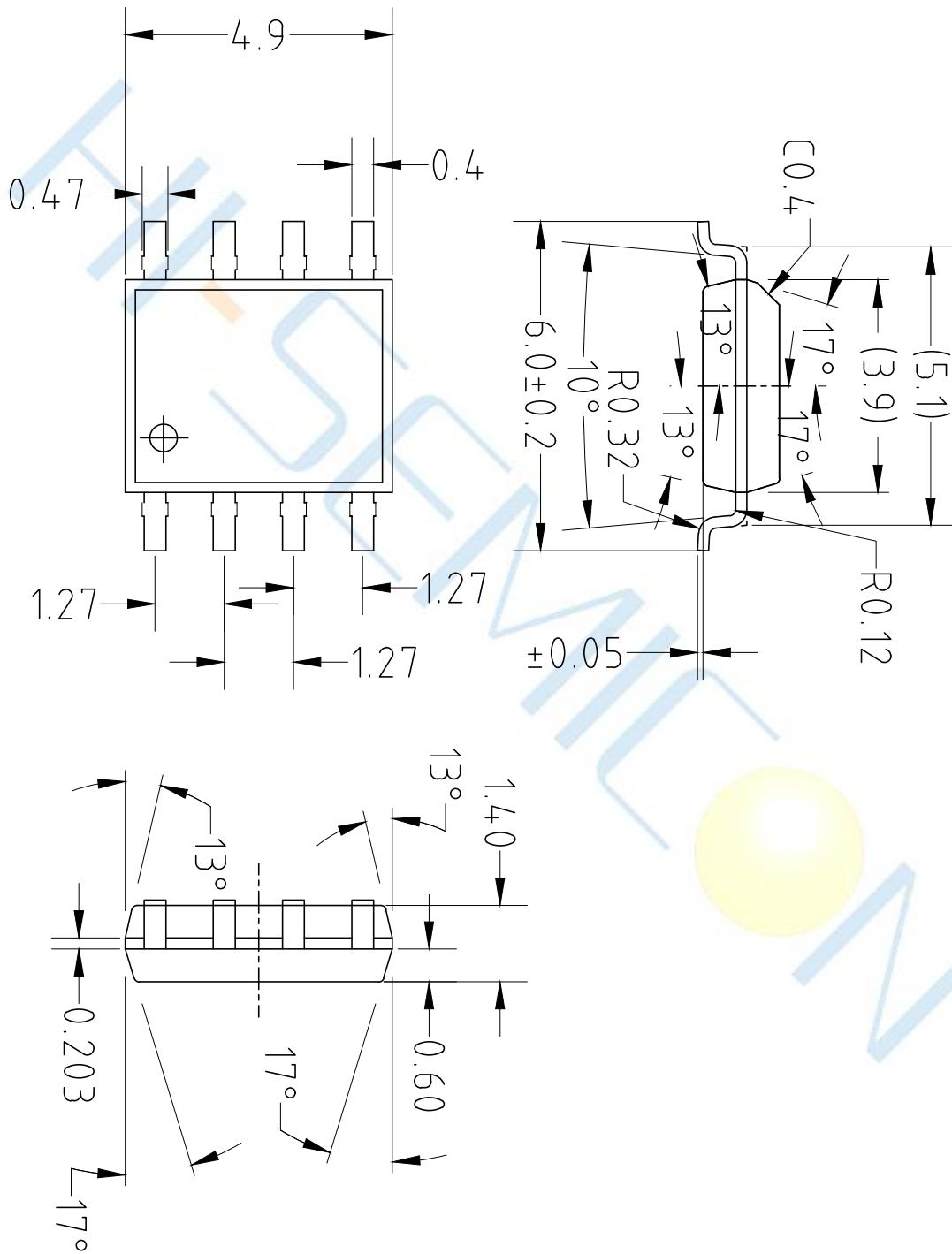


## Test Circuit



## Package Dimensions of SOP8-8L

Unit:mm



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